



INFORMATION DISCLOSURE CITATION		ATTY. DOCKET NO.	SERIAL NO.
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(Use several sheets if necessary)		APPLICANT	
		GLASPER et al	
		FILING DATE	GROUP
		January 11, 2005	2878

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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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TK	J. Huppertz et al, "Fast CMOS Imaging With High Dynamic Range" Proc. 1997 IEEE Workshop on Charge-Coupled Devices and Advanced Image Sensors
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